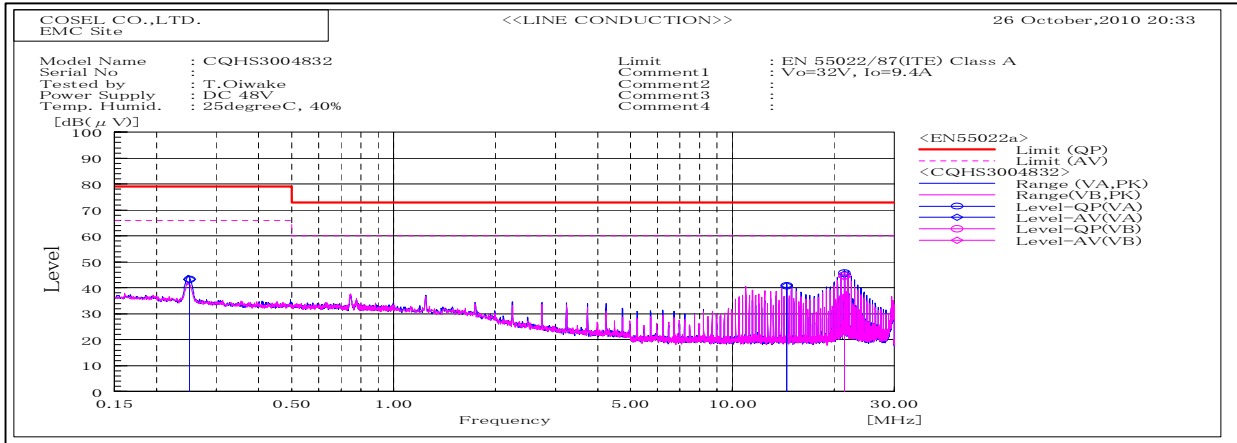
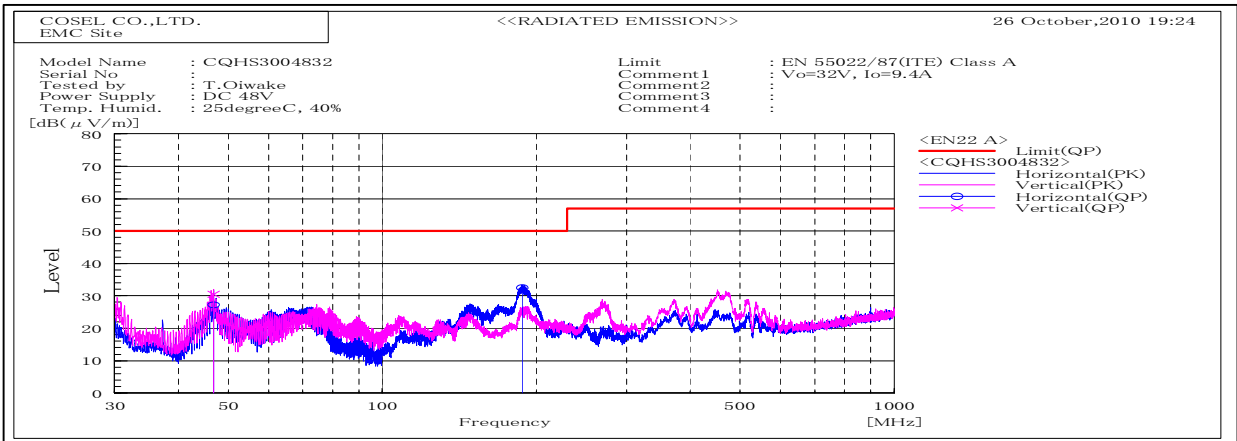


DATA SHEET		Date	26-Oct-10
Model	CQHS3004832	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Oiwake



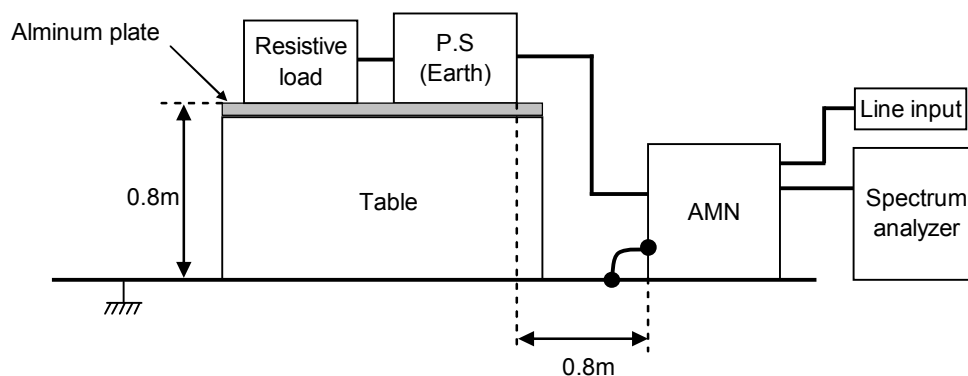
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.25002		VA	33.3	33.1	10.1	43.4	43.2	79	66	35.6	22.8	Pass	
14.45255		VA	30.1	30.2	10.7	40.8	40.9	73	60	32.2	19.1	Pass	
21.4307		VB	33.7	33.2	11	44.7	44.2	73	60	28.3	15.8	Pass	
21.42645		VA	34.9	34.4	10.9	45.8	45.3	73	60	27.2	14.7	Pass	



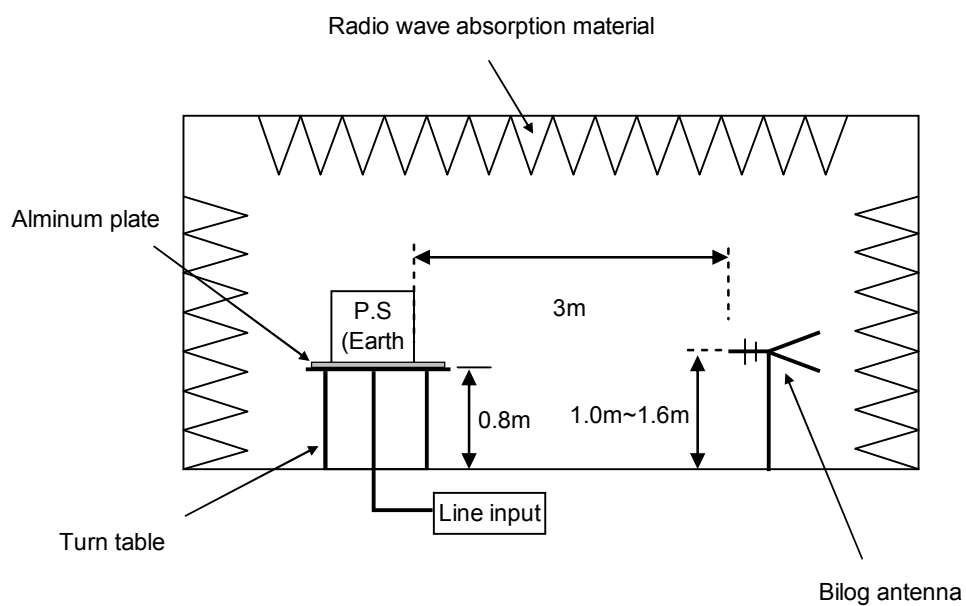
Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
46.842	H	Stable	49.4	-22.2	-22.2	27.2	27.2	50	22.8	Pass	152	344	
46.828	V	Stable	52.6	-22.2	-22.2	30.4	30.4	50	19.6	Pass	139	273	
188.014	H	Stable	54.6	-22.1	-22.1	32.5	32.5	50	17.5	Pass	131	351	

DATA SHEET		Date	26-Oct-10
Model	CQHS3004832	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Oiwake

1. Line conduction



2. Radiated emission

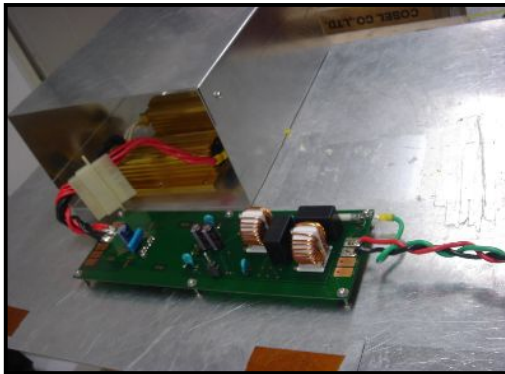


Test: EMI

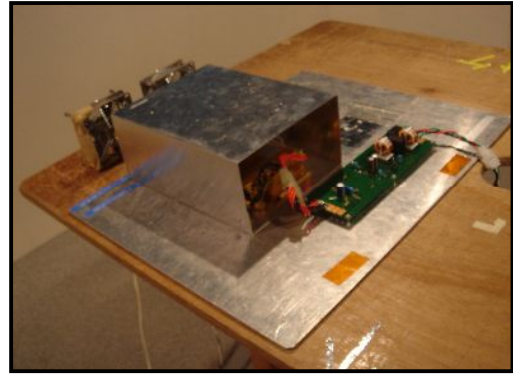
Model Name: CQHS300 Series

○ Photographs of Test Set-Up

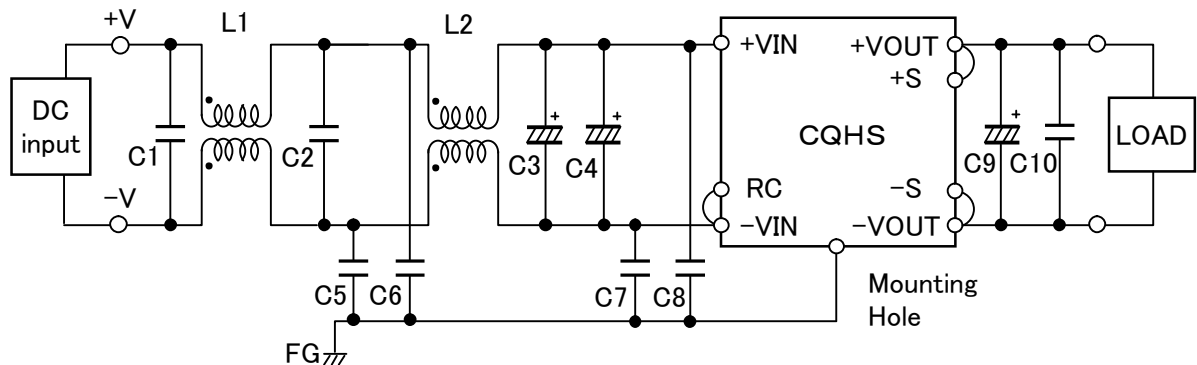
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1, L2 : 0.5mH 15A Inductor (SC-15-05J NEC TOKIN)
- C1, C2 : 310V 2.2 μ F Film capacitor (OKAYA ELEC)
- C3, C4 : 100V 68 μ F Electlic capacitor (LXV NIPPON CHEMI-CON)
- C5, C6, C7, C8 : 250V 4700pF Ceramic capacitor (Type KY MURATA)
- C9 : CQHS3004832 50V 470 μ F Electlic capacitor (LXZ NIPPON CHEMI-CON)
CQHS3004850 80V 330 μ F Electlic capacitor (KY NIPPON CHEMI-CON)
- C10 : 100V 0.1 μ F Film capacitor (Nitsuko)